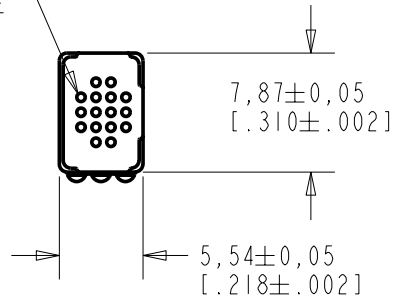


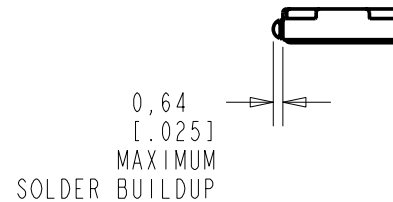
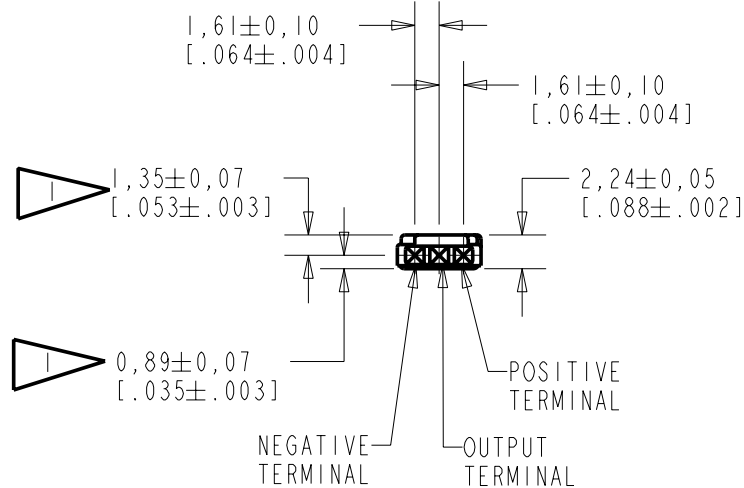
BT-21759-000
SHT 1.1

ALL HOLES LIE WITHIN
A $\varnothing 4,76$ [.1875] CIRCLE



NOTE:

LOCATED FROM TWO SURFACES FOR CUSTOMER CONVENIENCE. ONLY APPLICABLE FROM ONE SURFACE, NOT TO BE USED TOGETHER. HORIZONTAL LOCATION FOR TERMINAL CENTERED TO $\pm 0,17$ [.007].

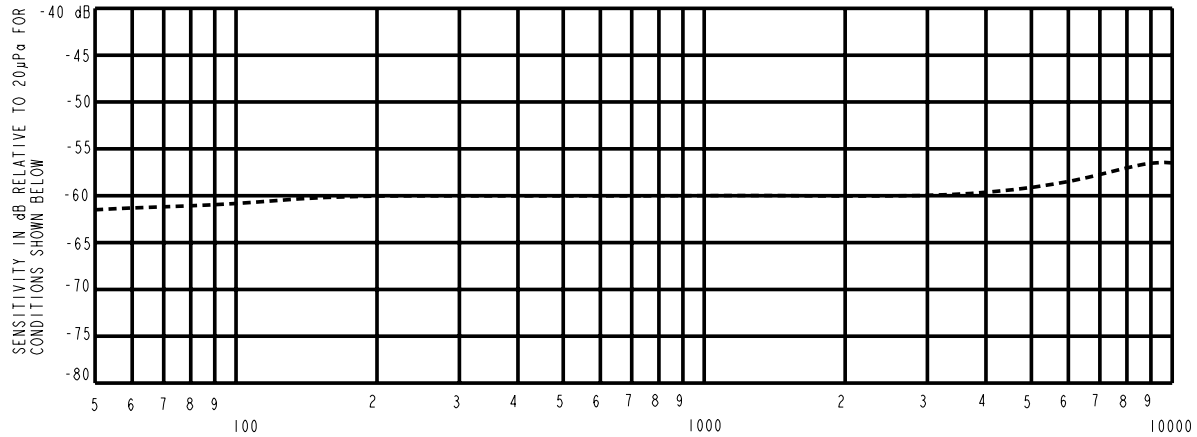


DIMENSIONS IN MILLIMETERS [INCHES]

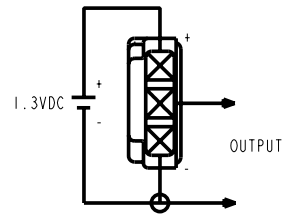
Revision	C.O. #	Implementation Date	RELEASE LEVEL	REVISION
			Released	A
A	MI0101192	7-26-06		

SCALE: 2:1		DR. BY LSY	DATE 7-26-06
DO NOT SCALE DRAWING			
TITLE: MICROPHONE		BT-21759-000	
OUTLINE DRAWING		SHT 1.1	
		APP. BY GJP	DATE 7-27-06
		APP. BY GJP	DATE 7-27-06

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FREQUENCY	SENSITIVITY			DEVICE CONFORMITY	
	MIN.	NOM.	MAX.	RANGE OF DEVIATION FROM 1 kHz	
100	---	-61.5	---	-4.0	+1.0
1000	-63.0	-60.0	-57.0	0	0
10000	---	-56.5	---	-1.0	+9.5



NOTES:

- CASE CONNECTED TO NEGATIVE TERMINAL.
- MICROPHONE TO BE FUNCTIONAL WITH 10 VDC SUPPLY.
- CONFORMS TO REQUIREMENTS SHOWN ON 'ELECTRET MICROPHONE ENVIRONMENTAL QUALIFICATION TEST, SHEET 2.2'.
- OPEN CIRCUIT SENSITIVITY IN dB RELATIVE TO 1.0 VOLT/MICROBAR (0.1 N/m²)

PORT LOCATION	DC SUPPLY	AMPLIFIER CURRENT DRAIN	SENSITIVITY CHANGE ON REDUCING SUPPLY TO 0.9VDC	"A" WEIGHTED NOISE (1 kHz EQUIV. SPL)	OUTPUT IMPEDANCE OHMS			CAPACITANCE ±50%	
					MIN.	NOM.	MAX.	1-2	1-3
KA	1.3V	50 µA MAX.	3 dB MAX.	30.0 dB MAX.	2000	3500	6000	NA	NA

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Revision	C.O. #	Implementation Date	RELEASE LEVEL	REVISION
A	M10101192	7-26-06	Released	A

WHEN TEST LIMITS ARE USED TO ESTABLISH INCOMING INSPECTION ACCEPTANCE/REJECTION CRITERIA, CORRELATION OF TEST EQUIPMENT WITH KNOWLES IS ALSO REQUIRED FOR ELIMINATION OF EQUIPMENT AND TEST METHOD VARIATION		DR. BY	DATE
		LSY	7-26-06
TITLE: MICROPHONE		CK. BY	DATE
PERFORMANCE SPECIFICATION		GJP	7-27-06
BT-21759-000		APP. BY	DATE
SHT 2.1		GJP	7-27-06

WHEN THESE TESTS ARE USED TO ESTABLISH PRODUCT QUALIFICATION, CORRELATION OF TEST EQUIPMENT WITH KNOWLES ELECTRONICS IS ALSO REQUIRED TO ELIMINATE EQUIPMENT AND TEST METHOD VARIATION.

BECAUSE THIS IS AN ACCELERATED LIFE TEST, IT FOLLOWS THAT THE UNITS WHICH HAVE BEEN TESTED WILL NOT QUALIFY AS IN-WARRANTY RETURNS. SINCE THESE TESTS ARE DESTRUCTIVE IN NATURE, DEVICES SUBJECTED TO THESE TESTS SHOULD NOT BE USED IN PRODUCTION.

1. ACCELERATED DAMP HEAT TEST.

- 1.1 PRECONDITIONING:
 - TIME - 16 HOURS
 - TEMPERATURE - 22°C ±1°C
 - HUMIDITY - 60% MAX. R.H.
- 1.2 TEST CONDITIONS:
 - TIME AT CONDITIONS: - 1000 HOURS
 - TEMPERATURE - 63°C ±1°C
 - HUMIDITY - 95% R.H. ±2%
 - VOLTAGE STRESS - DETAILED FIG. 1

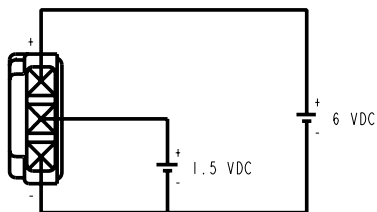


FIG. 1
(AVOID CONDENSATION FALLING ON UNITS UNDER TEST.)

1.3 INITIAL MEASUREMENTS:
AFTER PRECONDITIONING, MEASURE SENSITIVITY PER SHEET 2.1 OF THE APPLICABLE KNOWLES ELECTRONICS MICROPHONE PERFORMANCE SPECIFICATION.

1.4 TEST PROCEDURE:
INSERT UNIT(S) INTO TEST CHAMBER PER CONDITIONS OF 1.2.

1.5 RECOVERY:

- TIME - 2 HOURS
- TEMPERATURE - 22°C ± 1°C
- HUMIDITY - 60% MAX. R.H.

1.6 FINAL MEASUREMENTS:
MEASURE SENSITIVITY PER CONDITIONS DESCRIBED ON SHEET 2.1.

1.7 REQUIREMENT:
NO UNITS WILL BE INOPERATIVE FOLLOWING THE TEST AND RECOVERY CYCLE.

2. SHOCK TEST

2.1 PRECONDITIONING:

- TIME - 16 HOURS
- TEMPERATURE - 22°C ± 1°C
- HUMIDITY - 60% MAX. R.H.

2.2 TEST CONDITIONS:

- HALF-SINE IMPULSE DURATION - 100 MICROSECONDS
- PEAK AMPLITUDE - 20,000 g

SPURIOUS DEVIATIONS IN THE HALF-SINE IMPULSE CURVE SHALL BE REDUCED TO WHERE RESULTS ARE NOT APPRECIABLY AFFECTS. UNIT(S) TO BE SUBJECTED TO THE TEST CONDITIONS EITHER IN THE COVER UP OR COVER DOWN ORIENTATION.

2.3 INITIAL MEASUREMENTS:
AFTER PRECONDITIONING, MEASURE AND RECORD THE 1 kHz SENSITIVITY PER SHEET 2.1 OF THE APPLICABLE KNOWLES ELECTRONICS MICROPHONE PERFORMANCE SPECIFICATION.

2.4 TEST PROCEDURE:
STRESS UNIT(S) ACCORDING TO THE ABOVE 2.2 TEST CONDITIONS.

2.5 RECOVERY:
UNITS TO BE MEASURED IMMEDIATELY AFTER TEST CYCLE.

2.6 FINAL MEASUREMENTS:
MEASURE AND RECORD THE 1 kHz SENSITIVITY PER SHEET 2.1.

2.7 REQUIREMENT:
THE UNIT(S) SHALL SHOW A MAXIMUM CHANGE IN 1kHz SENSITIVITY (INITIAL TO FINAL) OF 1.0 dB AS A RESULT OF THE TEST CYCLE.

Revision	C.O. #	Implementation Date	RELEASE LEVEL	REVISION
			Released	A
A	M1010192	7-26-06		

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WHEN TEST LIMITS ARE USED TO ESTABLISH INCOMING INSPECTION ACCEPTANCE/REJECTION CRITERIA, CORRELATION OF TEST EQUIPMENT WITH KNOWLES IS ALSO REQUIRED FOR ELIMINATION OF EQUIPMENT AND TEST METHOD VARIATION		DR. BY	DATE
		LSY	7-26-06
TITLE: MICROPHONE		CK. BY	DATE
		GJP	7-27-06
PERFORMANCE SPECIFICATION		APP. BY	DATE
		GJP	7-27-06

BT-21759-000
SHT 2.2

Данный компонент на территории Российской Федерации

Вы можете приобрести в компании MosChip.

Для оперативного оформления запроса Вам необходимо перейти по данной ссылке:

<http://moschip.ru/get-element>

Вы можете разместить у нас заказ для любого Вашего проекта, будь то серийное производство или разработка единичного прибора.

В нашем ассортименте представлены ведущие мировые производители активных и пассивных электронных компонентов.

Нашей специализацией является поставка электронной компонентной базы двойного назначения, продукции таких производителей как XILINX, Intel (ex.ALTERA), Vicor, Microchip, Texas Instruments, Analog Devices, Mini-Circuits, Amphenol, Glenair.

Сотрудничество с глобальными дистрибьюторами электронных компонентов, предоставляет возможность заказывать и получать с международных складов практически любой перечень компонентов в оптимальные для Вас сроки.

На всех этапах разработки и производства наши партнеры могут получить квалифицированную поддержку опытных инженеров.

Система менеджмента качества компании отвечает требованиям в соответствии с ГОСТ Р ИСО 9001, ГОСТ РВ 0015-002 и ЭС РД 009

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